

Lecture 5: CMOS Transistor Theory

Assignment for 9/12

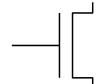
- ☐ Complete Lab2
- □ Text book reading sections 2.1T 2.3 (30 pages)

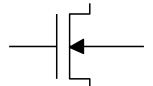
Outline

- Introduction
- MOS Capacitor
- nMOS I-V Characteristics
- pMOS I-V Characteristics
- ☐ Gate and Diffusion Capacitance

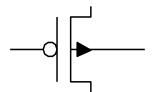
Introduction

- ☐ So far, we have treated transistors as ideal switches
- ☐ An ON transistor passes a finite amount of current
 - Depends on terminal voltages
 - Derive current-voltage (I-V) relationships
- ☐ Transistor gate, source, drain all have capacitance
 - $-I = C (\Delta V/\Delta t) \rightarrow \Delta t = (C/I) \Delta V$
 - Capacitance and current determine speed









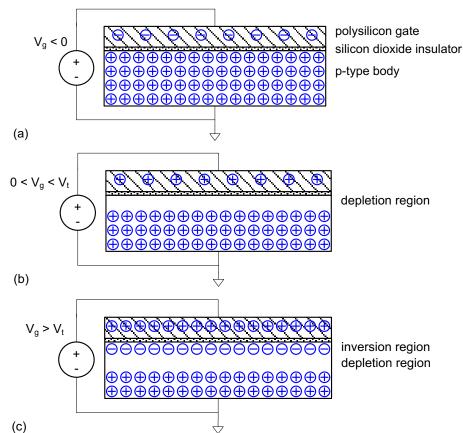
MOS Capacitor

☐ Gate and body form MOS

capacitor

Operating modes

- Accumulation
- Depletion
- Inversion



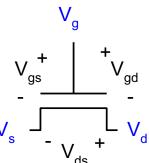
Terminal Voltages

■ Mode of operation depends on V_g, V_d, V_s

$$-V_{gs} = V_g - V_s$$

$$-V_{gd} = V_g - V_d$$

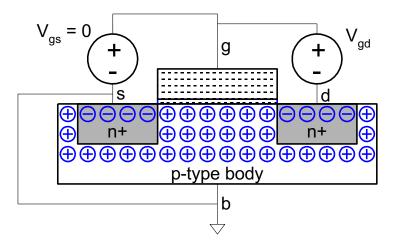
$$- V_{ds} = V_{d} - V_{s} = V_{gs} - V_{gd}$$



- ☐ Source and drain are symmetric diffusion terminals
 - By convention, source is terminal at lower voltage
 - Hence $V_{ds} \ge 0$
- □ nMOS body is grounded. First assume source is 0 too.
- ☐ Three regions of operation
 - Cutoff
 - Linear
 - Saturation

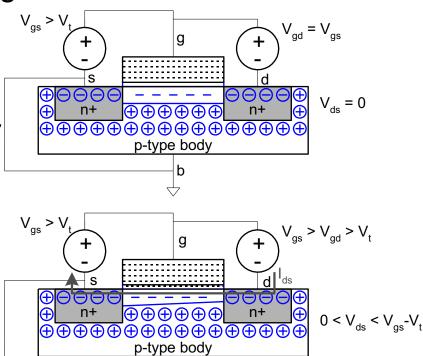
nMOS Cutoff

- No channel
- \Box $I_{ds} \approx 0$



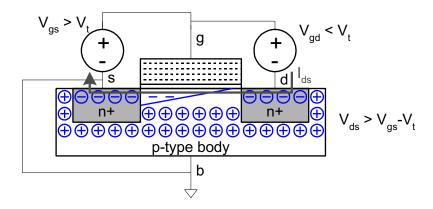
nMOS Linear

- ☐ Channel forms
- ☐ Current flows from d to s
 - e- from s to d
- \Box I_{ds} increases with V_{ds}
- ☐ Similar to linear resistor



nMOS Saturation

- ☐ Channel pinches off
- □ I_{ds} independent of V_{ds}
- We say current saturates
- □ Similar to current source

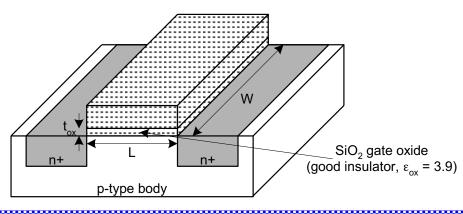


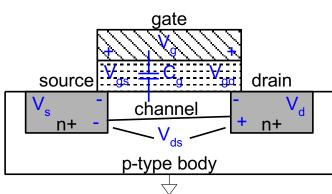
I-V Characteristics

- ☐ In Linear region, I_{ds} depends on
 - How much charge is in the channel?
 - How fast is the charge moving?

Channel Charge

- MOS structure looks like parallel plate capacitor while operating in inversions
 - Gate oxide channel
- \square Q_{channel} =





Carrier velocity

- ☐ Charge is carried by e-
- ☐ Electrons are propelled by the lateral electric field between source and drain
 - -E=
- ☐ Carrier velocity *v* proportional to lateral E-field
 - -v=
- ☐ Time for carrier to cross channel:
 - -t=

nMOS Linear I-V

- Now we know
 - How much charge Q_{channel} is in the channel
 - How much time t each carrier takes to cross

$$I_{ds} =$$

=

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nMOS Saturation I-V

- \Box If $V_{gd} < V_t$, channel pinches off near drain
 - When $V_{ds} > V_{dsat} =$
- Now drain voltage no longer increases current

$$I_{ds} =$$

=

nMOS I-V Summary

☐ Shockley 1st order transistor models

$$I_{ds} = \begin{cases} 0 & V_{gs} < V_t & \text{cutoff} \\ \beta \left(V_{gs} - V_t - \frac{V_{ds}}{2} \right) V_{ds} & V_{ds} < V_{dsat} & \text{linear} \\ \frac{\beta}{2} \left(V_{gs} - V_t \right)^2 & V_{ds} > V_{dsat} & \text{saturation} \end{cases}$$

Example

- We will be using a 0.6 μm process for your project
 - From AMI Semiconductor

$$- t_{ox} = 100 \text{ Å}$$

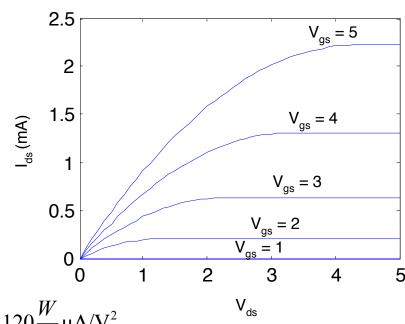
$$- \mu = 350 \text{ cm}^2/\text{V*s}$$

$$- V_t = 0.7 V$$

☐ Plot I_{ds} vs. V_{ds}

$$-V_{as} = 0, 1, 2, 3, 4, 5$$

- Use W/L = 4/2 λ

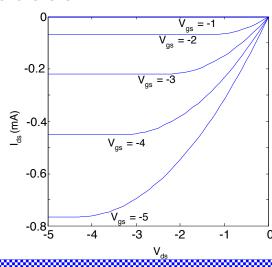


$$\beta = \mu C_{ox} \frac{W}{L} = (350) \left(\frac{3.9 \times 8.85 \cdot 10^{-14}}{100 \cdot 10^{-8}} \right) \left(\frac{W}{L} \right) = 120 \frac{W}{L} \, \mu \text{A/V}^2$$

pMOS I-V

- ☐ All dopings and voltages are inverted for pMOS
 - Source is the more positive terminal
- \Box Mobility μ_p is determined by holes
 - Typically 2-3x lower than that of electrons μ_n
 - 120 cm²/V•s in AMI 0.6 μm process
- ☐ Thus pMOS must be wider to provide same current
 - In this class, assume

$$\mu_n$$
 / μ_p = 3

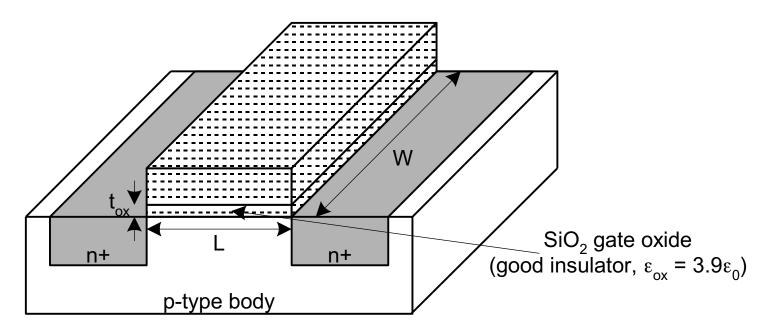


Capacitance

- □ Any two conductors separated by an insulator have capacitance
- Gate to channel capacitor is very important
 - Creates channel charge necessary for operation
- Source and drain have capacitance to body
 - Across reverse-biased diodes
 - Called diffusion capacitance because it is associated with source/drain diffusion

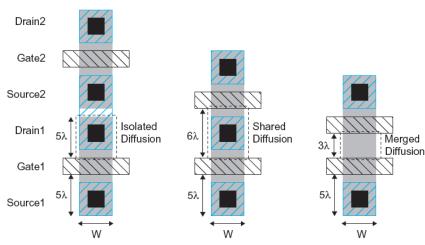
Gate Capacitance

- □ Approximate channel as connected to source
- \Box $C_{gs} = \varepsilon_{ox}WL/t_{ox} = C_{ox}WL = C_{permicron}W$
- C_{permicron} is typically about 2 fF/μm



Diffusion Capacitance

- $C_{\rm sh}, C_{\rm db}$
- Undesirable, called *parasitic* capacitance
- Capacitance depends on area and perimeter
 - Use small diffusion nodes
 - Comparable to C_a for contacted diff
 - $-\frac{1}{2}$ C_q for uncontacted
 - Varies with process



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